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INTERNATIONAL STANDARD

Synthetic quartz crystal – Specifications and guidelines for use

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SYNTHETIC QUARTZ CRYSTAL – SPECIFICATIONS AND GUIDELINES FOR USE

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International Standard IEC 60758 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

This fifth edition cancels and replaces the fourth edition, published in 2008. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- order rearrangement and review of terms and definitions;
- abolition as a standard of the infrared absorbance coefficient $\alpha_{3\ 410}$;
- addition of the α value measurement explanation by FT-IR equipment in annex;
- addition of the synthetic quartz crystal standards for optical applications.

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The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

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